### **Electrical Characteristics**

Parameter	Symbol	Min	Тур	Max	Units	Conditions
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	30			V	$V_{GS} = 0V, I_{D} = 250\mu A$
Static Drain-Source On-Resistance	R <sub>DS(on)</sub>		17	25	mΩ	$V_{GS} = 4.5V, I_D = 7.0A$ ②
Gate Threshold Voltage	$V_{GS(th)}$	1.0		3.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Drain-Source Leakage Current	I <sub>DSS</sub>			100	μA	$V_{DS} = 30V, V_{GS} = 0$
				20		$V_{DS} = 24V, V_{GS} = 0$
				100		$V_{DS} = 24V, V_{GS} = 0, T_{J} = 100^{\circ}C$
Gate-Source Leakage Current*	I <sub>GSS</sub>			±100	nΑ	$V_{GS} = \pm 20V$
Total Gate Charge*	$Q_G$		9.5	14		$V_{GS} = 5V, I_{D} = 7.0A$
Pre-Vth Gate-Source Charge	Q <sub>GS1</sub>		2.3			V <sub>DS</sub> = 16V
Post-Vth Gate-Source Charge	Q <sub>GS2</sub>		1.0		nC	
Gate-to-Drain Charge	$Q_{GD}$		2.4		lic	
Switch Charge (Q <sub>gs2</sub> + Q <sub>gd</sub> )	Q <sub>SW</sub>		3.4	5.2		
Output Charge*	Q <sub>OSS</sub>		12	16.8		$V_{DS} = 16V, V_{GS} = 0$
Gate Resistance	$R_G$	0.9		2.8	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>		6.3			V <sub>DD</sub> = 16V
Rise Time	t <sub>r</sub>		1.2			$I_D = 7A$
Turn-Off Delay Time	t <sub>d(off)</sub>		11		ns	$V_{GS} = 5V, R_G = 2\Omega$
Fall Time	t <sub>f</sub>		2.2			Resistive Load

### **Source-Drain Ratings and Characteristics**

Parameter	Symbol	Min	Тур	Max	Units	Conditions
Diode Forward Voltage*	V <sub>SD</sub>			1.2	V	$I_{S} = 7.0A ② , V_{GS} = 0V$
Reverse Recovery Charge ®	Q <sub>rr</sub>		64		nC	$di/dt = 700A/\mu s$ $V_{DS} = 16V, V_{GS} = 0V, I_{S} = 7.0A$
Reverse Recovery Charge (with Parallel Schottsky) <sup>(4)</sup>	Q <sub>rr(s)</sub>		41			$di/dt = 700A/\mu s$ , (with 10BQ040) $V_{DS} = 16V$ , $V_{GS} = 0V$ , $I_{S} = 7.0A$

- - Device are 100% tested to these parameters.

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## IRF7807V

# Power MOSFET Selection for DC/DC Converters

### **Control FET**

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the  $R_{\rm ds(on)}$  of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by;

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms  $Q_{gs2}$  and  $Q_{oss}$  which are new to Power MOSFET data sheets.

 $Q_{gs2}$  is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements,  $Q_{gs1}$  and  $Q_{gs2}$ , can be seen from Fig 1.

 $Q_{gs2}$  indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached (t1) and the time the drain current rises to  $I_{dmax}$  (t2) at which time the drain voltage begins to change. Minimizing  $Q_{gs2}$  is a critical factor in reducing switching losses in Q1.

 $Q_{\mbox{\tiny oss}}$  is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure 2 shows how  $Q_{\mbox{\tiny oss}}$  is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's  $C_{\mbox{\tiny ds}}$  and  $C_{\mbox{\tiny dg}}$  when multiplied by the power supply input buss voltage.

Drain Current

Gate Voltage

t2
t3

VGTH

t0

Drain Voltage

Figure 1: Typical MOSFET switching waveform

### **Synchronous FET**

The power loss equation for Q2 is approximated by;

$$\begin{aligned} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{aligned}$$

\*dissipated primarily in Q1.

## **IRF7807V**

For the synchronous MOSFET Q2,  $R_{\rm ds(on)}$  is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge  $Q_{\rm oss}$  and reverse recovery charge  $Q_{\rm r}$  both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and  $V_{\rm in}$ . As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn

the MOSFET on, resulting in shoot-through current . The ratio of  $Q_{\rm gd}/Q_{\rm gs1}$  must be minimized to reduce the potential for Cdv/dt turn on.

Spice model for IRF7807V can be downloaded in machine readable format at www.irf.com.

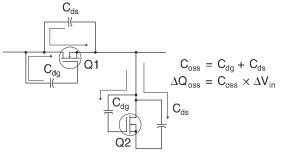
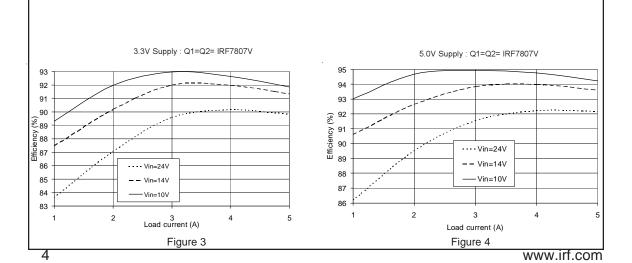
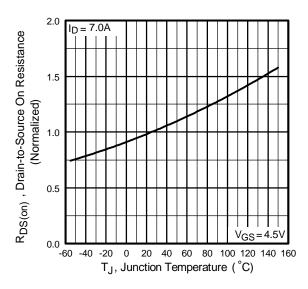


Figure 2: Q<sub>oss</sub> Characteristic

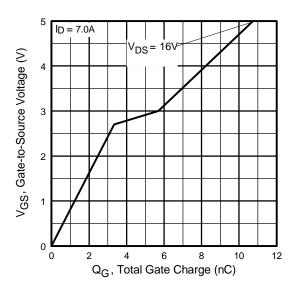
### **Typical Mobile PC Application**

The performance of these new devices has been tested in circuit and correlates well with performance predictions generated by the system models. An advantage of this new technology platform is that the MOSFETs it produces are suitable for both control FET and synchronous FET applications. This has been demonstrated with the 3.3V and 5V converters. (Fig 3 and Fig 4). In these applications the same MOSFET IRF7807V was used for both the control FET (Q1) and the synchronous FET (Q2). This provides a highly effective cost/performance solution.





**Fig 5.** Normalized On-Resistance Vs. Temperature



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

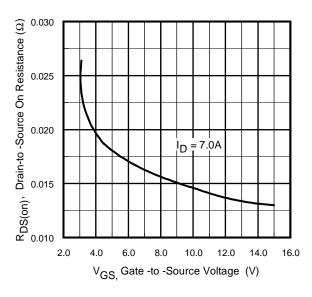
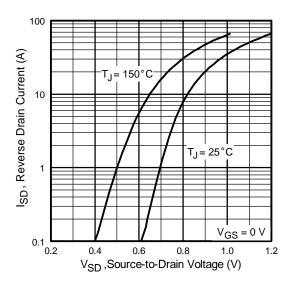


Fig 7. On-Resistance Vs. Gate Voltage



**Fig 8.** Typical Source-Drain Diode Forward Voltage

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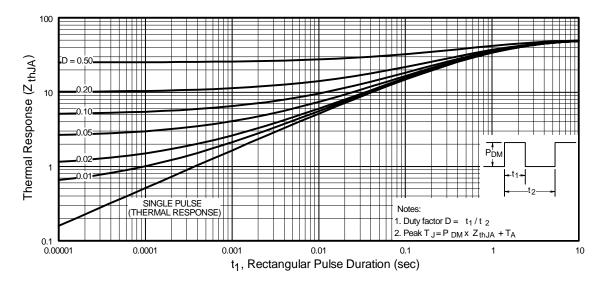
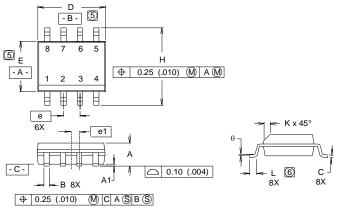


Figure 9. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

## **IRF7807V**

## **SO-8 Package Details**

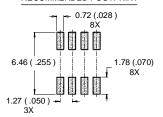


### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M-1982.
- 2. CONTROLLING DIMENSION: INCH.
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA.
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.006).
- 6 DIMENSIONS IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE..

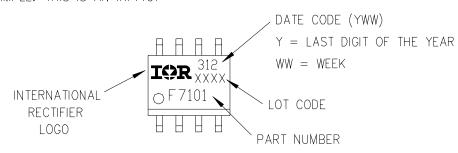
INC	HES	MILLIMETERS			
MIN	MAX	MIN	MAX		
.0532	.0688	1.35	1.75		
.0040	.0098	0.10	0.25		
.014	.018	0.36	0.46		
.0075	.0098	0.19	0.25		
.189	.196	4.80	4.98		
.150	.157	3.81	3.99		
.050 I	BASIC	1.27 BASIC			
.025 I	BASIC	0.635 BASIC			
.2284	.2440	5.80	6.20		
.011	.019	0.28	0.48		
0.16	.050	0.41	1.27		
0°	8°	0°	8°		
	MIN .0532 .0040 .014 .0075 .189 .150 .025 I .2284 .011 .0.16	.0532 .0688 .0040 .0098 .014 .018 .0075 .0098 .189 .196 .150 .157 .050 BASIC .025 BASIC .2284 .2440 .011 .019 0.16 .050	MIN         MAX         MIN           .0532         .0688         1.35           .0040         .0098         0.10           .014         .018         0.36           .0075         .0098         0.19           .189         .196         4.80           .150         .157         3.81           .050         BASIC         1.27 IIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIIII		

RECOMMENDED FOOTPRINT



## **SO-8 Part Marking**

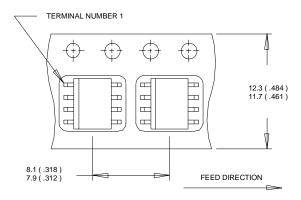
EXAMPLE: THIS IS AN IRF7101



# IRF7807V

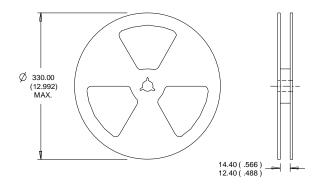
### International IOR Rectifier

### **SO-8 Tape and Reel**



#### NOTES:

- CONTROLLING DIMENSION: MILLIMETER.
  ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).
  OUTLINE CONFORMS TO EIA-481 & EIA-541.



- NOTES:

  1. CONTROLLING DIMENSION: MILLIMETER.

  2. OUTLINE CONFORMS TO EIA-481 & EIA-541.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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